

Ion scattering spectroscopy
 Scanning Auger microscopy
 Ultraviolet photoemission spectroscopy
 Data dependent acquisition software
imaging XPS
15 μ m selected area XPS
 Auger electron spectroscopy



AXIS SUPRA⁺

The AXIS Supra⁺ from Kratos Analytical combines the highest XPS performance in spectroscopic and imaging modes with unrivalled levels of automation.

The AXIS Supra⁺ supports additional analytical techniques including AES, UPS, ISS and SIMS without compromising state-of-the-art XPS performance.

EnviroESCATM – ESCA under Environmental Conditions

SPECSTM

The Beginning of a New Era

EnviroESCATM

- Fast Quality Control
- High Throughput Analysis
- Controllable Atmosphere
- Revolutionary Technology
- Ergonomic all-in-one Design
- Fully Automated and Software Controlled

